Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	_
10/757,405	TAKINOSAWA ET AL.	
Examiner	Art Unit	_
David E. Martinez	2181	

	SEAR	CHED	
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED				
Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East see attached	7/25/2006	DM		
Databases: US Patents, US PGPUBS, USOCR, EPO, Derwent, IBM_TDB.	7/25/2006	DM		
710/2,62,72,100,300,301,305,313.ccls .with keywords and text search	7/25/2006	DM		
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